



Thematic Network on Silicon on Insulator Technology, Devices and Circuits.  
[IST-1-506653-CA]

## EUROSOI "Who is Who" Guide

### *Name of the organisation*

<i>Organization Legal name:</i>	<b>Philips Semiconductors B.V.</b>
<i>Organization short name:</i>	Philips
<i>Internet homepage:</i>	<b>www.philips.com</b>

### *Contact person*

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<i>Postal Address</i>	Binzstr. 44, CH-8045 Zurich, Switzerland or Gerstweg 2, NL-6534AE Nijmegen, The Netherlands		

### **Other Senior Researchers:** (up to 10 names, please include e-mail address)

J.-H. Fock ([johann.fock@philips.com](mailto:johann.fock@philips.com)), F. Murray ([franck.murray@philips.com](mailto:franck.murray@philips.com)), J. Koch ([jochen.koch@philips.com](mailto:jochen.koch@philips.com)), R. Verhaar ([rob.verhaar@philips.com](mailto:rob.verhaar@philips.com)), P. Wessels ([piet.wesseld@philips.com](mailto:piet.wesseld@philips.com)), J. v.d. Pol ([jacob.van.der.pol@philips.com](mailto:jacob.van.der.pol@philips.com)), S. Gopalan ([sudha.gopalan@philips.com](mailto:sudha.gopalan@philips.com))

### **Experience and expertise fields:** (50 words)

Double-gate devices, full-depleted double gate, bipolar devices in SOI, high voltage (850V) BCD processes on SOI, power processes for audio and automotive applications (60-120V, 2-10A), SOI in volume production, qualification, life-testing, reliability assessment, modelling of SOI devices (bipolar, CMOS, DMOS).

### **Facilities and Equipment:**

Full production facilities for volume production of SOI ICs, characterization and measurement equipment (parameter analyser, curve tracer up to 2kV, 10A), full life-test equipment, failure analysis.

### **Three last international research projects:**

ENCAST (EU Network for Co-ord. Of Adv. Semiconductor Technology)  
Top Nano (EU Program on Nanoelectronics, Swiss subproject)  
Good-Die II (EU Network on known good die standards)